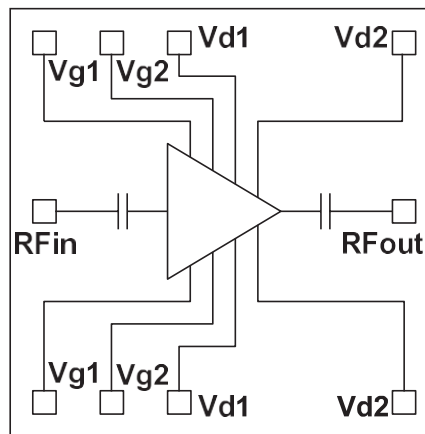


Features

- Frequency: 2-6GHz
- Gain: 25dB
- Psat: +44dBm@28V
- PAE: 35%V@Psat
- Power Supply: 28V@1A
- Die Size : 4.54 x 4.82 mm

Typical Applications

- Test Instrumentation
- Microwave Radio & VSAT
- Military & Space
- Telecom Infrastructure
- Fiber Optics

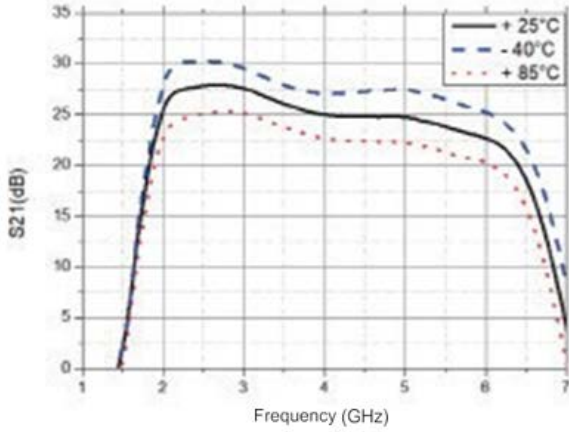
Functional Block Diagram

Electrical Specifications

TA = +25°C, Vd1 = Vd2 = +28V, Vg1 = Vg2 = -3.2V (On-wafer Measurement Results)

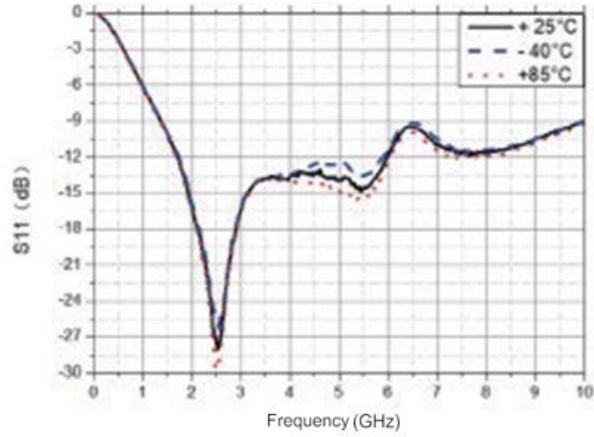
Parameters	Min.	Typ.	Max.	Units
Frequency		2-6		GHz
Gain		25		dB
Psat		44		dBm
PAE		35		%
Input Return Loss		15		dB
Output Return Loss		7		dB
Operating Current		1		A



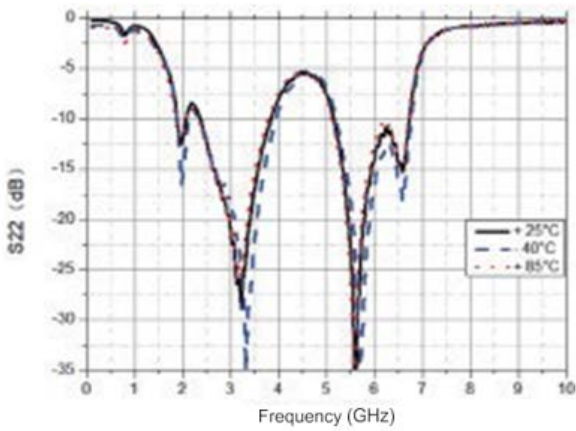
Gain vs. Frequency



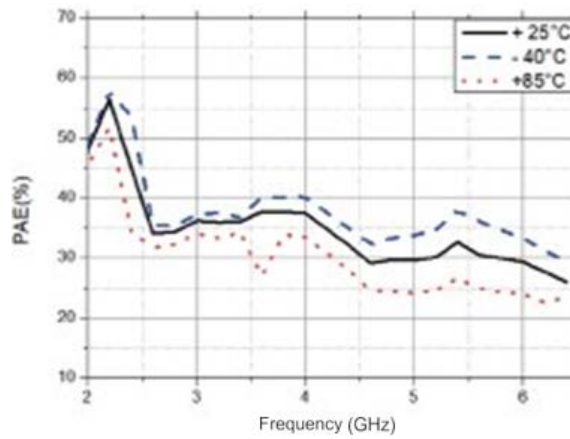
Input Return Loss vs. Frequency



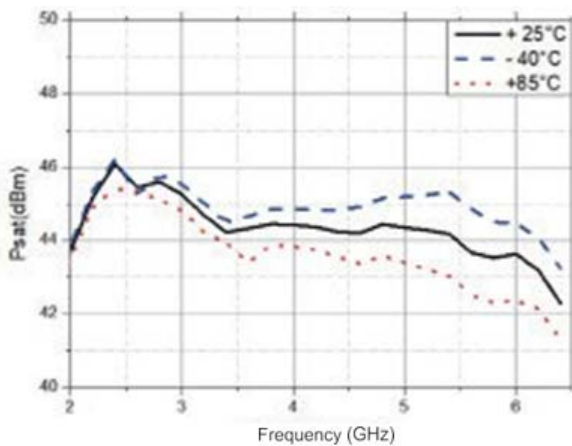
Output Return Loss vs. Frequency



PAE vs. Frequency

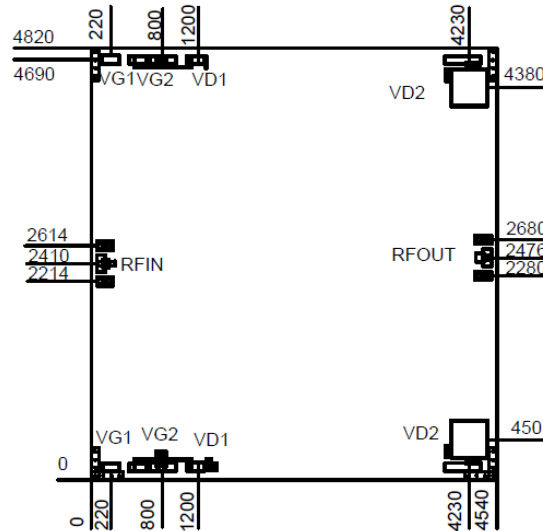


Psat vs. Frequency

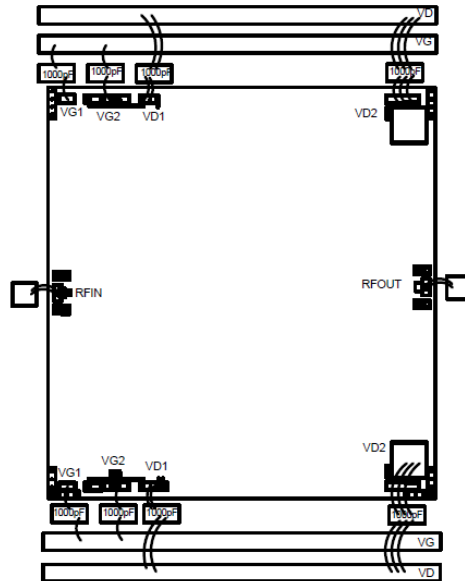




Outline Drawing: All Dimensions in μm



Assembly Drawing (Bond testing)



Notes:

1. Die thickness: 100um
2. Typical bond pad is 100*100 μm^2
3. Bond pad metalization: Gold
4. Backside metalization: Gold
5. Backside of the die (GND)
6. No connection required for unlabeled bond pads

Maximum Ratings:

1. Supply voltage: +30V
2. RF Input power: +27dBm
3. Operating temperature: -55°C to +85°C
4. Storage temperature: -65°C to +150°C